

N-channel 600 V, 0.35 Ω typ., 11 A MDmesh™ M2 Power MOSFET in a TO-220FP wide creepage package

Datasheet - production data

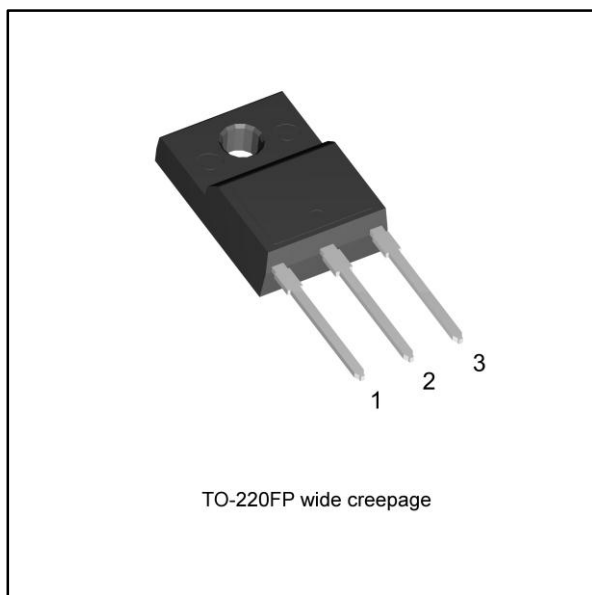
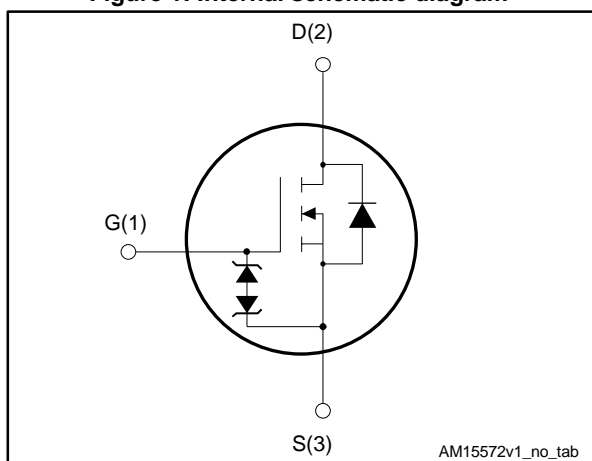


Figure 1: Internal schematic diagram



Features

| Order code | V _{DS} | R _{DS(on)} max | I _D |
|-------------|-----------------|-------------------------|----------------|
| STFH13N60M2 | 600 V | 0.38 Ω | 11 A |

- Extremely low gate charge
- Excellent output capacitance (C_{oss}) profile
- 100% avalanche tested
- Zener-protected
- Wide creepage distance of 4.25 mm between the pins

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

The TO-220FP wide creepage package provides increased surface insulation for Power MOSFETs to prevent failure due to arcing, which can occur in polluted environments.

Table 1: Device summary

| Order code | Marking | Package | Packaging |
|-------------|---------|------------------------|-----------|
| STFH13N60M2 | 13N60M2 | TO-220FP wide creepage | Tube |

Contents

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1 Electrical ratings

Table 2: Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|-------------------------|---|-------------------|--------------------|
| V_{GS} | Gate-source voltage | ± 25 | V |
| I_D | Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$ | 11 ⁽¹⁾ | A |
| I_D | Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$ | 7 ⁽¹⁾ | A |
| I_{DM} ⁽²⁾ | Drain current (pulsed) | 44 | A |
| P_{TOT} | Total dissipation at $T_C = 25\text{ }^{\circ}\text{C}$ | 25 | W |
| V_{ISO} | Insulation withstand voltage (RMS) from all three leads to external heat sink ($t = 1\text{ s}$; $T_C = 25\text{ }^{\circ}\text{C}$) | 2500 | V |
| dv/dt ⁽³⁾ | Peak diode recovery voltage slope | 15 | V/ns |
| dv/dt ⁽⁴⁾ | MOSFET dv/dt ruggedness | 50 | |
| T_{stg} | Storage temperature range | - 55 to 150 | $^{\circ}\text{C}$ |
| T_j | Operating junction temperature range | | |

Notes:⁽¹⁾Limited by maximum junction temperature.⁽²⁾Pulse width limited by safe operating area.⁽³⁾ $I_{SD} \leq 11\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$; $V_{DS(\text{peak})} < V_{(BR)DSS}$, $V_{DD} = 400\text{ V}$ ⁽⁴⁾ $V_{DS} \leq 480\text{ V}$

Table 3: Thermal data

| Symbol | Parameter | Value | Unit |
|----------------|---|-------|-----------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case max | 5 | $^{\circ}\text{C}/\text{W}$ |
| $R_{thj-amb}$ | Thermal resistance junction-ambient max | 62.5 | $^{\circ}\text{C}/\text{W}$ |

Table 4: Avalanche characteristics

| Symbol | Parameter | Value | Unit |
|----------|--|-------|------|
| I_{AR} | Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax}) | 2.8 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_j = 25^{\circ}\text{C}$, $I_D = I_{AR}$; $V_{DD} = 50\text{ V}$) | 125 | mJ |

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 5: On /off states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|----------------------|-----------------------------------|--|------|------|------|------|
| V _{(BR)DSS} | Drain-source breakdown voltage | I _D = 1 mA, V _{GS} = 0 V | 600 | | | V |
| I _{DSS} | Zero gate voltage drain current | V _{DS} = 600 V, V _{GS} = 0 V | | | 1 | μA |
| | | V _{DS} = 600 V, V _{GS} = 0 V, T _C = 125 °C ⁽¹⁾ | | | 100 | μA |
| I _{GSS} | Gate-body leakage current | V _{GS} = ± 25 V, V _{DS} = 0 V | | | ±10 | μA |
| V _{GS(th)} | Gate threshold voltage | V _{DS} = V _{GS} , I _D = 250 μA | 2 | 3 | 4 | V |
| R _{DS(on)} | Static drain-source on-resistance | V _{GS} = 10 V, I _D = 5.5 A | | 0.35 | 0.38 | Ω |

Notes:

⁽¹⁾Defined by design, not subject to production test.

Table 6: Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-------------------------------------|-------------------------------|--|------|------|------|------|
| C _{iss} | Input capacitance | V _{DS} = 100 V, f = 1 MHz, V _{GS} = 0 V | - | 580 | - | pF |
| C _{oss} | Output capacitance | | - | 32 | - | pF |
| C _{rss} | Reverse transfer capacitance | | - | 1.1 | - | pF |
| C _{oss eq.} ⁽¹⁾ | Equivalent output capacitance | V _{DS} = 0 to 480 V, V _{GS} = 0 V | - | 120 | - | pF |
| R _G | Intrinsic gate resistance | f = 1 MHz open drain | - | 6.6 | - | Ω |
| Q _g | Total gate charge | V _{DD} = 480 V, I _D = 11 A, V _{GS} = 10 V (see Figure 15: "Test circuit for gate charge behavior") | - | 17 | - | nC |
| Q _{gs} | Gate-source charge | | - | 2.5 | - | nC |
| Q _{gd} | Gate-drain charge | | - | 9 | - | nC |

Notes:

⁽¹⁾C_{oss eq.} is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.

Table 7: Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------------|---------------------|---|------|------|------|------|
| t _{d(on)} | Turn-on delay time | V _{DD} = 300 V, I _D = 5.5 A, R _G = 4.7 Ω, V _{GS} = 10 V (see Figure 14: "Test circuit for resistive load switching times" and Figure 19: "Switching time waveform") | - | 11 | - | ns |
| t _r | Rise time | | - | 10 | - | ns |
| t _{d(off)} | Turn-off delay time | | - | 41 | - | ns |
| t _f | Fall time | | - | 9.5 | - | ns |

Table 8: Source drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|--|------|------|------|---------------|
| I_{SD} | Source-drain current | | - | | 11 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | | 44 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $I_{SD} = 11\text{ A}$, $V_{GS} = 0\text{ V}$ | - | | 1.6 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 11\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 60\text{ V}$ (see Figure 16: "Test circuit for inductive load switching and diode recovery times") | - | 297 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 2.8 | | μC |
| I_{RRM} | Reverse recovery current | | - | 18.5 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 11\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 60\text{ V}$, $T_j = 150\text{ }^\circ\text{C}$, (see Figure 16: "Test circuit for inductive load switching and diode recovery times") | - | 394 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 3.8 | | μC |
| I_{RRM} | Reverse recovery current | | - | 19 | | A |

Notes:

(1)Pulse width limited by safe operating area.

(2)Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

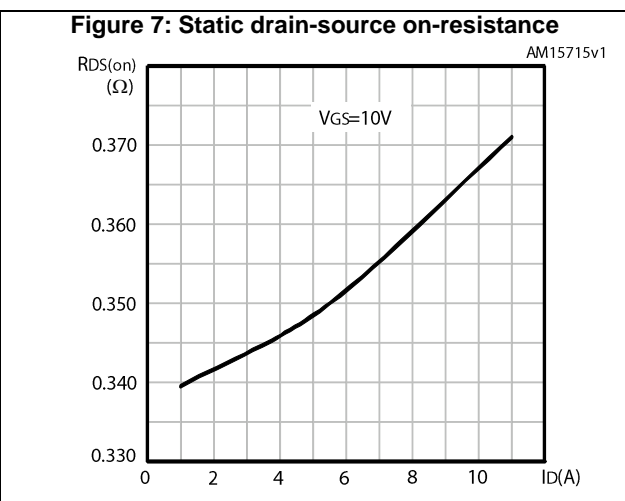
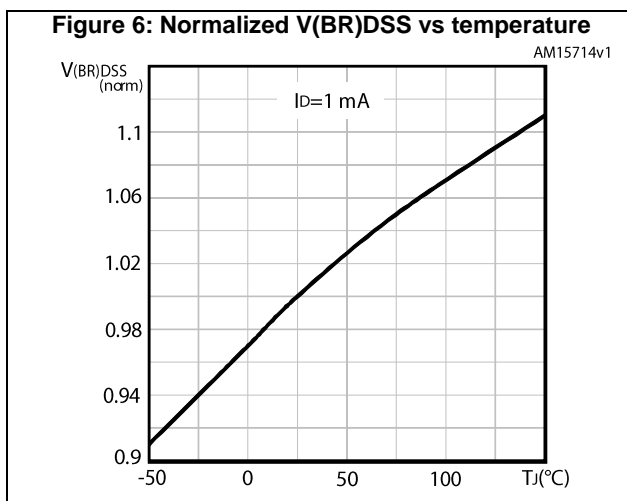
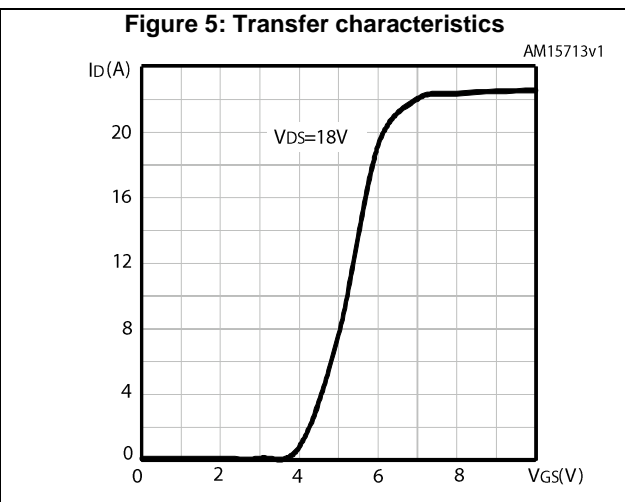
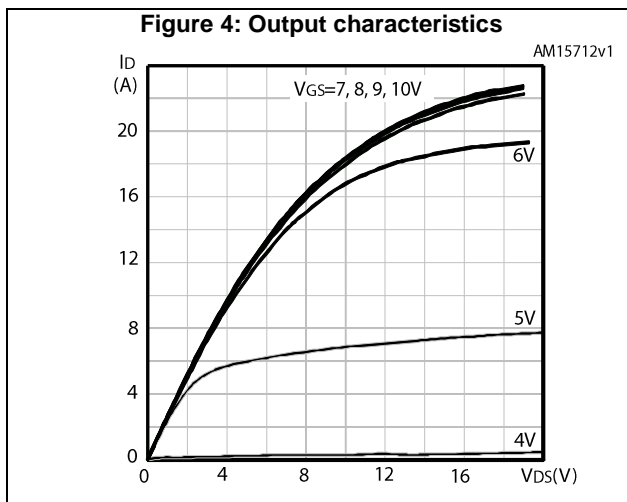
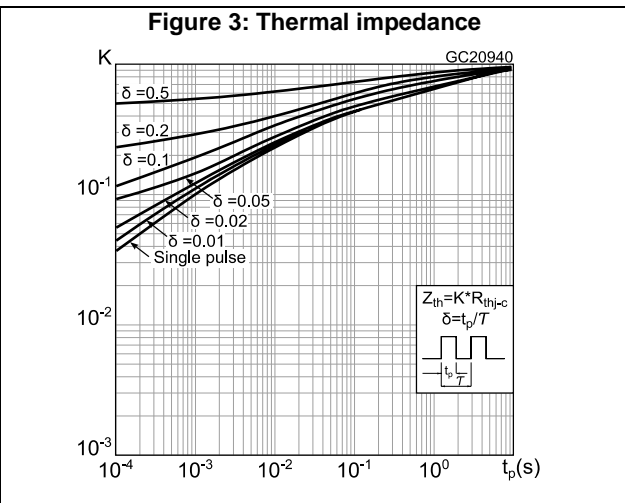
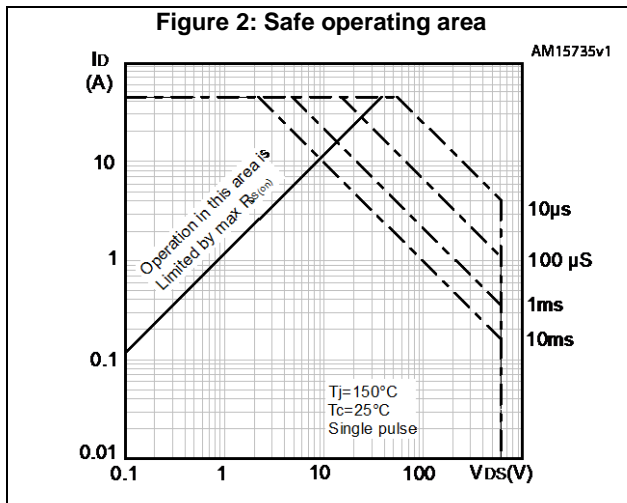


Figure 8: Gate charge vs gate-source voltage

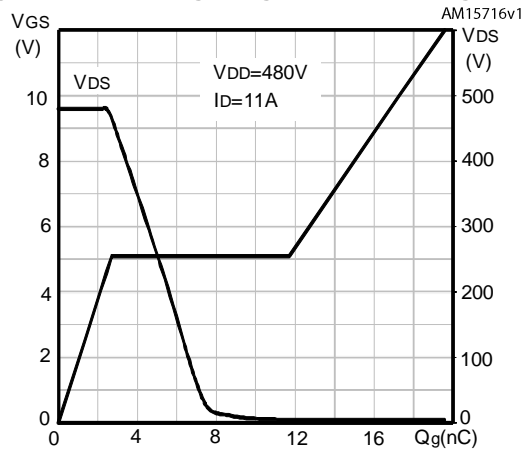


Figure 9: Capacitance variations

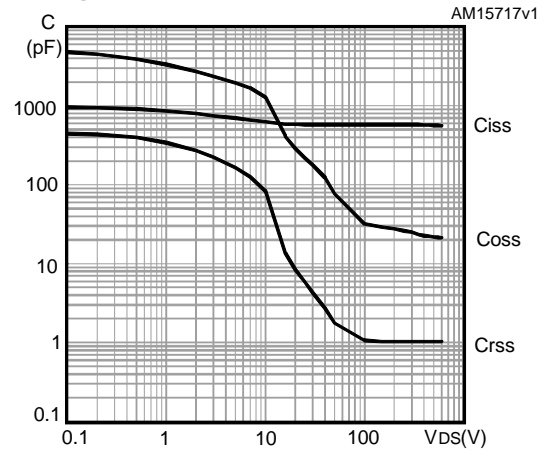


Figure 10: Normalized gate threshold voltage vs temperature

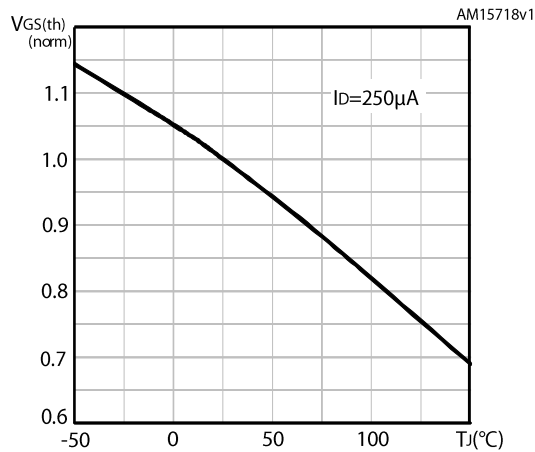


Figure 11: Normalized on-resistance vs temperature

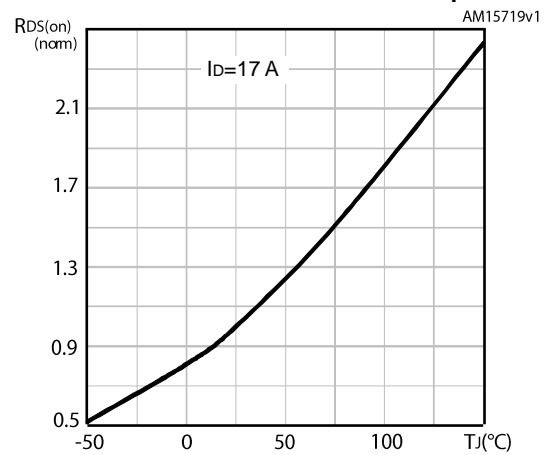


Figure 12: Source-drain diode forward characteristics

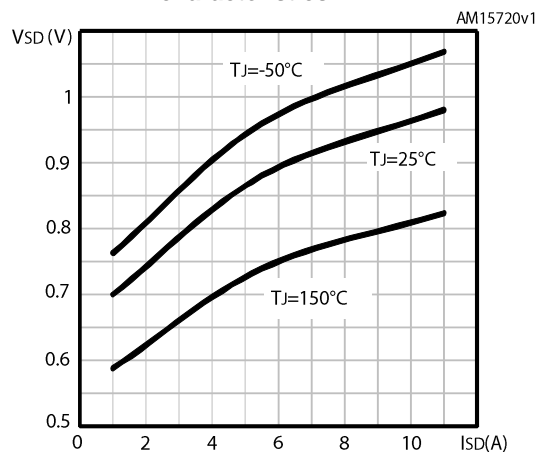
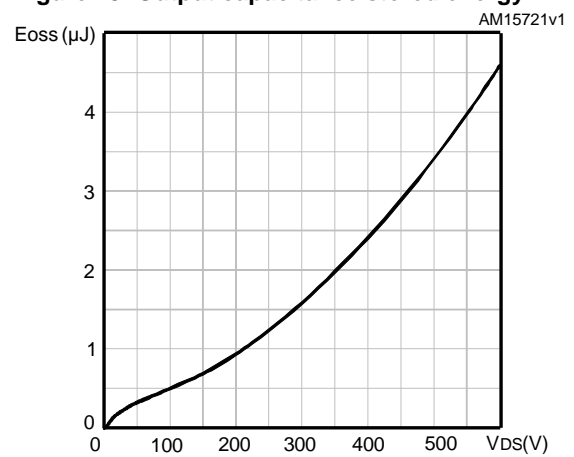
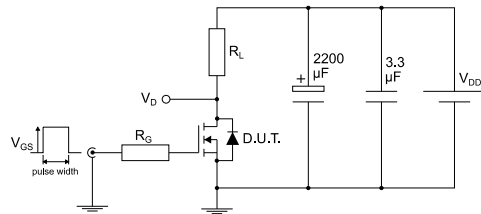


Figure 13: Output capacitance stored energy



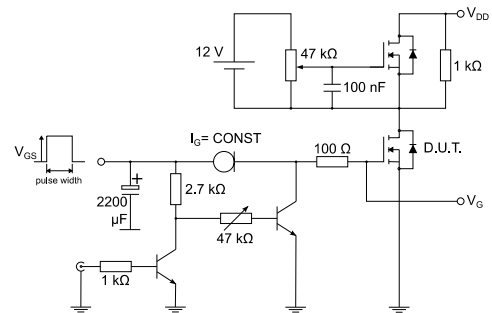
3 Test circuits

Figure 14: Test circuit for resistive load switching times



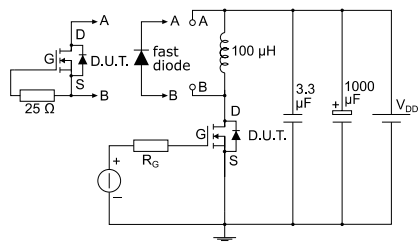
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Figure 15: Test circuit for gate charge behavior



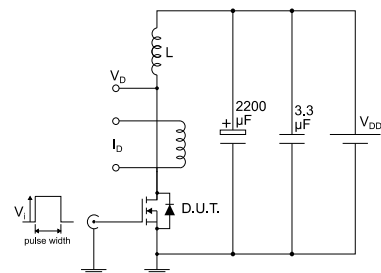
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Figure 16: Test circuit for inductive load switching and diode recovery times



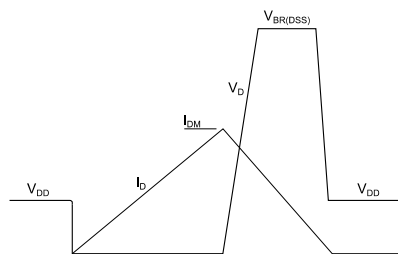
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Figure 17: Unclamped inductive load test circuit



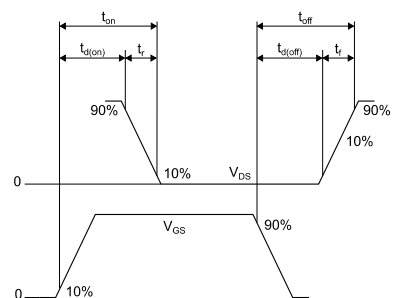
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Figure 18: Unclamped inductive waveform



AM01472v1

Figure 19: Switching time waveform



AM01473v1

4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 TO-220FP wide creepage package information

Figure 20: TO-220FP wide creepage package outline

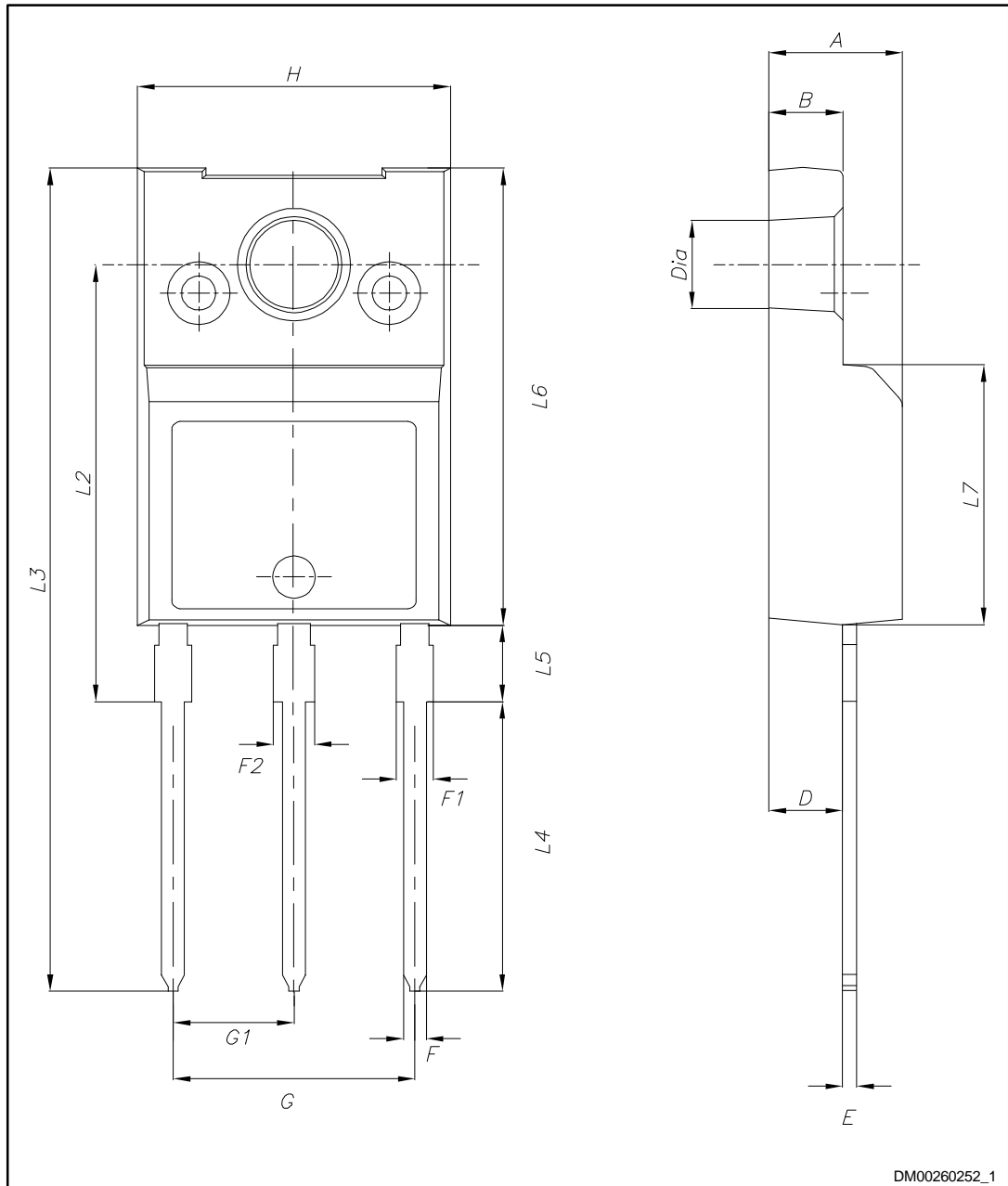


Table 9: TO-220FP wide creepage package mechanical data

| Dim. | mm | | |
|------|-------|-------|-------|
| | Min. | Typ. | Max. |
| A | 4.60 | 4.70 | 4.80 |
| B | 2.50 | 2.60 | 2.70 |
| D | 2.49 | 2.59 | 2.69 |
| E | 0.46 | | 0.59 |
| F | 0.76 | | 0.89 |
| F1 | 0.96 | | 1.25 |
| F2 | 1.11 | | 1.40 |
| G | 8.40 | 8.50 | 8.60 |
| G1 | 4.15 | 4.25 | 4.35 |
| H | 10.90 | 11.00 | 11.10 |
| L2 | 15.25 | 15.40 | 15.55 |
| L3 | 28.70 | 29.00 | 29.30 |
| L4 | 10.00 | 10.20 | 10.40 |
| L5 | 2.55 | 2.70 | 2.85 |
| L6 | 16.00 | 16.10 | 16.20 |
| L7 | 9.05 | 9.15 | 9.25 |
| Dia | 3.00 | 3.10 | 3.20 |

5 Revision history

Table 10: Document revision history

| Date | Revision | Changes |
|-------------|----------|---|
| 12-May-2016 | 1 | Initial release |
| 10-Jun-2016 | 2 | Document status promoted from preliminary to production data. |

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